# EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|---|---|---|---|---|---|---|
| L1 | 571947 | (wafer$1 or semicondudor$l or chip$l or subtrat$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:12 |
| L2 | 2 | L1 and select$3 and review adj data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:13 |
| L3 | 2 | L1 and review adj data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:13 |
| L4 | 638 | L1 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:14 |
| L5 | 134 | L1 and review same data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:14 |
| L6 | 0 | L5 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| L7 | 0 | L5 and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| L8 | 1 | L5 and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| L9 | 11 | L4 and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |

| L10 | 5 | L9 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:16 |
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| L11 | 5 | L10 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:16 |
| L12 | 1 | L11 and (user or operator or human)and page and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:17 |
| L13 | 1 | L11 and (user or operator or human)and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:17 |
| L14 | 9 | L4 and(detect$3 or determining) and (defect or fault or flaw)and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:19 |
| L15 | 13 | learning and(knowledge-based or knowledge adj based) and database and automatic and defect adj classification | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| L16 | 10 | L15 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| L17 | 0 | L16 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| L18 | 1 | L16 and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:22 |
| L19 | 8 | L16 and(wafer$1 or semicondudor$l or chip$l or subtrat$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:24 |

| L20 | 8 | L19 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:24 |
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| L21 | 6 | L20 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:43 |
| L22 | 5 | L20 and descriptor adj (defect or fault or flaw) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:46 |
| S1 | 571947 | (wafer$1 or semicondudor$l or chip$l or subtrat$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:27 |
| S2 | 1 | S1 and automatic and defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:29 |
| S3 | 1 | automatic and defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S4 | 1 | S1 and defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S5 | 1 | defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S6 | 2 | defect adj classification and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S7 | 82 | defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |

| S8 | 19 | S7 and (wafer$1 or semicondudor$l or chip$l or subtrat$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S9 | 17 | S8 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:36 |
| S10 | 12 | S8 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:36 |
| S11 | 24 | ((DIRK) near2 (SOENKSEN)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:36 |
| S12 | 11 | ((RALF) near2 (FRIEDRICH)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S13 | 1 | ((ANDREAS) near2 (DRAEGER)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S14 | 2 | ((DETLEF) near2 (SCHUPP)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S16 | 2 | ((THIN) near2 ("VAN LUU")).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:39 |
| S17 | 3 | ((WOLFGANG) near2 (LANGER)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:39 |
| S18 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:40 |
| S19 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:40 |
| S20 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:41 |
| S21 | 0 | S12 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:41 |
| S22 | 0 | S13 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:43 |

| S23 | 3 | S10 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:46 |
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| S24 | 638382 | S23 and select$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:47 |
| S25 | 0 | S23 and select$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:47 |
| S26 | 18 | S7 and select$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:48 |
| S27 | 0 | S26 and parameters and learning adj node | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:49 |
| S28 | 0 | S26 and parameters and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:49 |
| S29 | 17 | S26 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:49 |
| S30 | 2 | S1 and S7 and S24 and S29 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:56 |
| S31 | 2 | S30 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:56 |
| S32 | 18 | S7 and S26 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:57 |

| S33 | 16 | S32 and @ad< "20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:58 |
| S34 | 20 | S1 and automatic and defect adj recognition | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:00 |
| S35 | 638382 | S34 and select$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:01 |
| S36 | 4 | S34 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:33 |
| S37 | 1 | S34 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:34 |
| S38 | 0 | S37 and @ad< "20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:34 |
| S39 | 16 | S34 and @ad< "20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S40 | 0 | S39 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S41 | 2 | S39 and learning | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S42 | 16 | S26 and @ad< "20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:39 |

| S43 | 0 | S42 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
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| S44 | 0 | S42 and learning near mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
| S45 | 0 | S42 and learning near3 mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
| S46 | 11 | S42 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
| S47 | 598 | S1 and select$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:44 |
| S48 | 340 | S47 and @ad< "20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:44 |
| S49 | 1 | S48 and input and user and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:45 |
| S50 | 1 | S48 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:46 |
| S51 | 4 | S48 and alignment adj procedure | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:46 |
| S52 | 0 | S8 and automatic adj defect and recognition and(detect$3 or determining)same (defect or flaw or fault)same(assign$3 or test$3 or evaluat$3)same descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |

| S53 | 0 | S48 and automatic adj defect and recognition and(detect$3 or determining)same (defect or flaw or fault)same(assign$3 or test$3 or evaluat$3)same descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
|-----|----|-------|-------|-----|-----|-------|
| S54 | 1 | automatic adj defect and recognition and(detect$3 or determining)same (defect or flaw or fault)same(assign$3 or test$3 or evaluat$3)same descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
| S55 | 11 | automatic adj defect and recognition and(detect$3 or determining)and(defect or flaw or fault)and(assign$3 or test$3 or evaluat$3)and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S56 | 5 | S55 and @ad< "20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S57 | 1 | S56 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S58 | 0 | S57 and edit adj recipe | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:05 |
| S59 | 0 | S57 and edit | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:05 |
| S60 | 0 | S57 and memory adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:07 |
| S61 | 1 | S57 and circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:07 |
| S62 | 0 | S61 and logic adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:08 |

| S63 | 0 | S61 and blank adj wafer$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:08 |
| S64 | 1 | S56 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 14:02 |

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